Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/655,423	JUNG ET AL.	
Examiner	Art Unit	
Binh X. Tran	1765	

	SEAR	CHED	
Class	Subclass	Date	Examiner
438	696	11/17/2005	ВТ
438	700	11/17/2005	ВТ
438	706	11/17/2005	вт
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
438	696	11/17/2005	ВТ		
438	700	11/17/2005	ВТ		
438	706	11/17/2005	вт		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Update search	11/17/2005	вт		
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